



Description

11 Megapixel CCD camera - 5 fps

Prosilica GE4000 is a very high-resolution CCD camera with Gigabit Ethernet output (GigE Vision®). GE4000 features the high-quality 35 mm format OnSemi KAI-11002 CCD image sensor that provides exceptionally high resolution, sensitivity, and dynamic range. Options

- IR cut filter (monochrome cameras)
- Sensor Class 1 or 2; fixed cover glass with microlenses; class 1 or 2 with taped cover glass with or without microlenses
- Various lens mounts

Specifications

Prosilica GE	4000
Interface	IEEE 802.3 1000baseT
Resolution	4008 × 2672
Sensor	OnSemi KAI-11002
Sensor type	CCD Progressive
Cell size	9 µm
Lens mount	F-Mount
Max frame rate at full resolution	5 fps
ADC	12 bit
On-board FIFO	32 Mbyte
Output	
Bit depth	8/12 bit
Mono modes	Mono8, Mono12, Mono12Packed



Prosilica GE	4000
Color modes RGB	n/a
Raw modes	BayerGR8, BayerGR12, BayerGR12Packed
General purpose inputs/outputs (GPIOs)	
TTL I/Os	1 input, 3 outputs (with galvanic isolation)
RS-232	1
Operating conditions/dimensions	
Operating temperature	0°C +50°C
Power requirements (DC)	5V - 24V
Power consumption (@12 V)	6 W
Mass	402 g
Body dimensions (L × W × H in mm)	110 × 66 × 66 including connectors, w/o tripod and lens
Regulations	CE, FCC Class A, RoHS (2011/65/EU)



Features

Features include:

- Defect masking for columns
- ROI, DSP subregion (selectable ROI for auto features)
- Binning
- Auto gain (manual gain control: 0 to 34 dB)
- Auto exposure (manual exposure controls: 140 µs to 68.7 s)



- Auto white balance
- StreamBytesPerSecond (easy bandwidth control)
- Stream hold
- Sync out modes: Trigger ready, input, exposing, readout, imaging, strobe, GPO
- Global shutter (digital shutter)
- Recorder and Multiframe acquisition modes
- Event channel
- Chunk data
- Storable user sets



Technical drawing









*Nominal value. Add 0.33 mm for color cameras





Applications

Prosilica GE4000 is ideal for a wide range of applications requiring very high resolution. These include:

- LCD panel inspection
- Semiconductor wafer inspection
- Solar panel inspection
- Aerial photography
- 3-D metrology
- General machine vision
- Public security
- Surveillance
- Traffic imaging (Intelligent Traffic Systems)
- Embedded systems
- OEM applications